

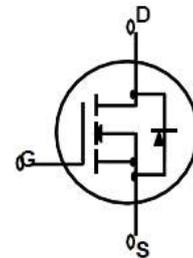
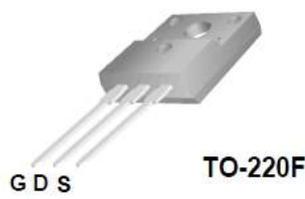
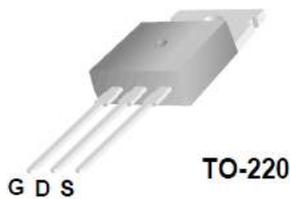
650V N-Channel MOSFET

General Description

This Power MOSFET is produced using SL semi's advanced planar stripe DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as DC/DC converters and high efficiency switching for power management in portable and battery operated products.

Features

- 4.0A, 650V, $R_{DS(on)} = 3.0\Omega @ V_{GS} = 10V$
- Low gate charge (typical 15nC)
- High ruggedness
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability



Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	SLS4N65	SSS4N65	Units
V_{DSS}	Drain-Source Voltage		650	V
I_D	Drain Current - Continuous ($T_C = 25^\circ\text{C}$)		4.0	A
I_{DM}	Drain Current - Pulsed (Note 1)		16	A
V_{GSS}	Gate-Source Voltage		± 30	V
E_{AS}	Single Pulsed Avalanche Energy (Note 2)		180	mJ
E_{AR}	Repetitive Avalanche Energy (Note 1)		10	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5	V/ns
P_D	Power Dissipation ($T_C = 25^\circ\text{C}$)		104	W
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	$^\circ\text{C}$
T_L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	$^\circ\text{C}$

* Drain current limited by maximum junction temperature.

N-CHANNEL MOSFET

SI4N65

Electrical Characteristics

$T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\ \mu\text{A}$	650	--	--	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\ \mu\text{A}$, Referenced to 25°C	--	0.6	--	$\text{V}/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 650\text{ V}, V_{GS} = 0\text{ V}$	--	--	1	μA
		$V_{DS} = 520\text{ V}, T_C = 125^\circ\text{C}$	--	--	10	μA
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30\text{ V}, V_{DS} = 0\text{ V}$	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30\text{ V}, V_{DS} = 0\text{ V}$	--	--	-100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\ \mu\text{A}$	2.0	--	4.5	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{ V}, I_D = 2.0\text{ A}$	--	2.5	3.0	Ω
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS} = 25\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	--	560	--	pF
C_{oss}	Output Capacitance		--	55	--	pF
C_{rss}	Reverse Transfer Capacitance		--	7	--	pF
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 325\text{ V}, I_D = 4.0\text{ A},$ $R_G = 25\ \Omega$ (Note 4, 5)	--	10	--	ns
t_r	Turn-On Rise Time		--	40	--	ns
$t_{d(off)}$	Turn-Off Delay Time		--	40	--	ns
t_f	Turn-Off Fall Time		--	50	--	ns
Q_g	Total Gate Charge	$V_{DS} = 520\text{ V}, I_D = 4.0\text{ A},$ $V_{GS} = 10\text{ V}$ (Note 4, 5)	--	16	-	nC
Q_{gs}	Gate-Source Charge		--	2.5	--	nC
Q_{gd}	Gate-Drain Charge		--	6.5	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain-Source Diode Forward Current		--	--	4.0	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current		--	--	16	A
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = 4.0\text{ A}$	--	--	1.4	V
t_{rr}	Reverse Recovery Time	$V_{GS} = 0\text{ V}, I_S = 4.0\text{ A},$	--	300	--	ns
Q_{rr}	Reverse Recovery Charge	$di_F / dt = 100\text{ A}/\mu\text{s}$ (Note 4)	--	2.0	--	μC

Notes:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. $L = 22\text{ mH}, I_{AS} = 4.0\text{ A}, V_{DD} = 25\text{ V}, R_G = 25\ \Omega$, Starting $T_J = 25^\circ\text{C}$
3. $I_{SD} \leq 4.0\text{ A}, di/dt \leq 200\text{ A}/\mu\text{s}, V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse width $\leq 300\ \mu\text{s}$, Duty cycle $\leq 2\%$
5. Essentially independent of operating temperature

Typical Characteristics

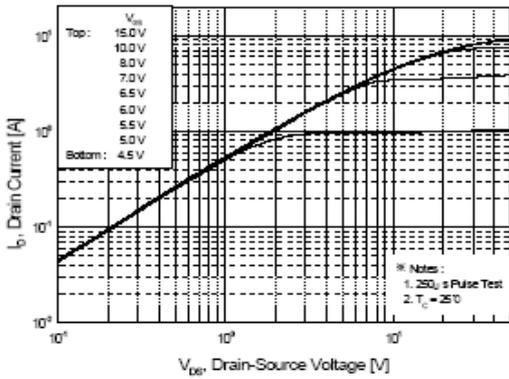


Figure 1. On-Region Characteristics

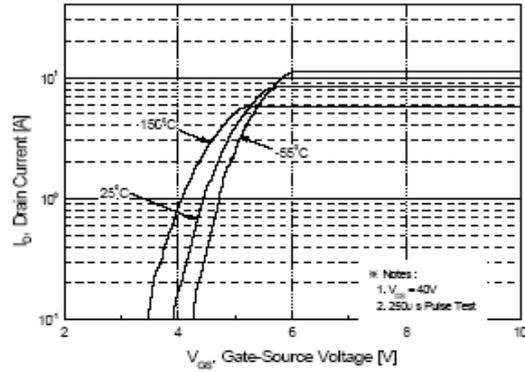


Figure 2. Transfer Characteristics

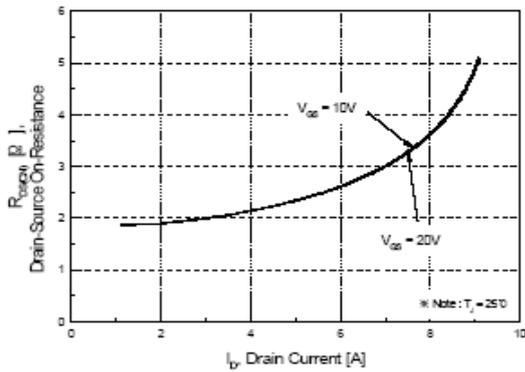


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

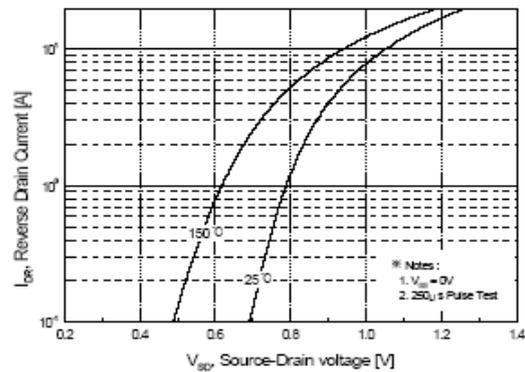


Figure 4. Body Diode Forward Voltage Variation with Source Current

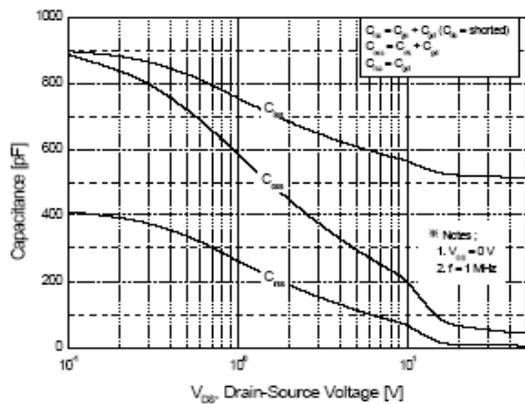


Figure 5. Capacitance Characteristics

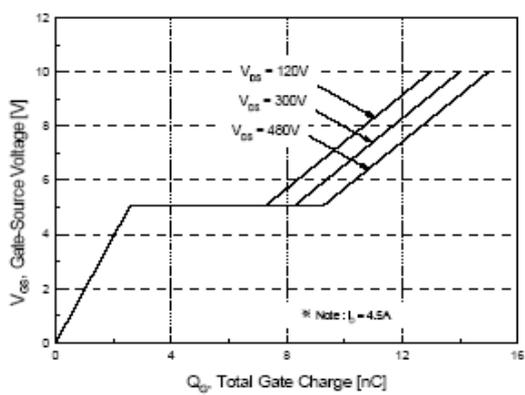


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

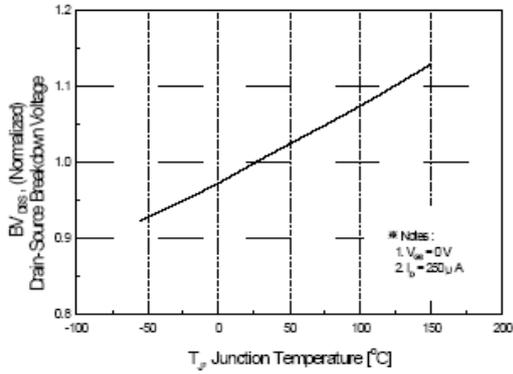


Figure 7. Breakdown Voltage Variation vs Temperature

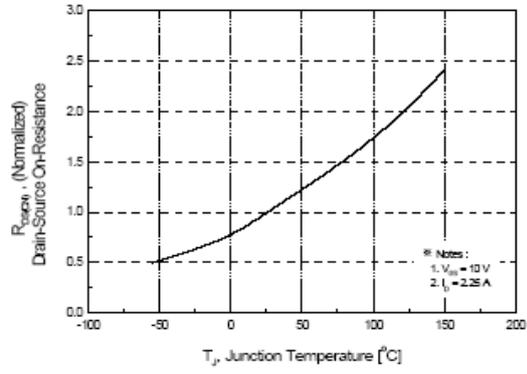


Figure 8. On-Resistance Variation vs Temperature

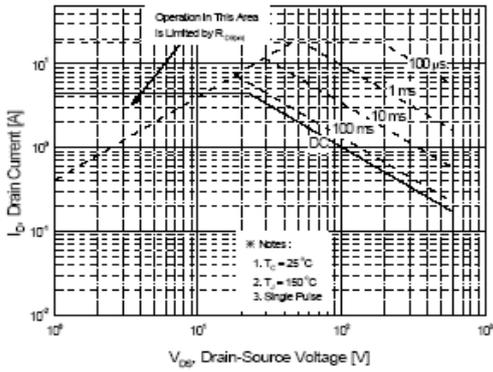


Figure 9-1. Maximum Safe Operating Area for SSS4N65C

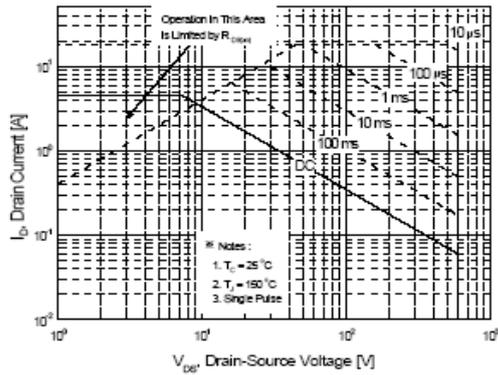


Figure 9-2. Maximum Safe Operating Area for SSS4N65C

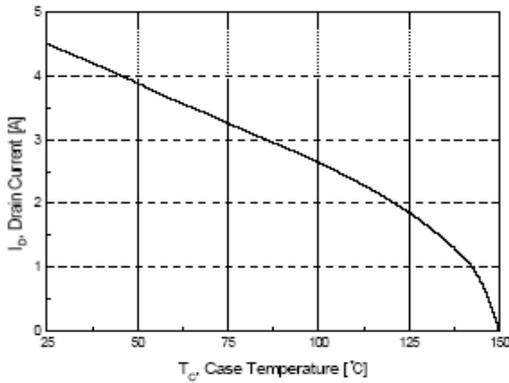


Figure 10. Maximum Drain Current vs Case Temperature

Typical Characteristics (Continued)

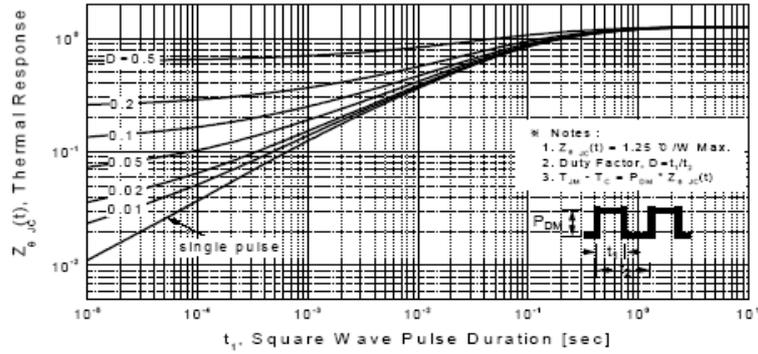


Figure 11-1. Transient Thermal Response Curve for SSS4N65

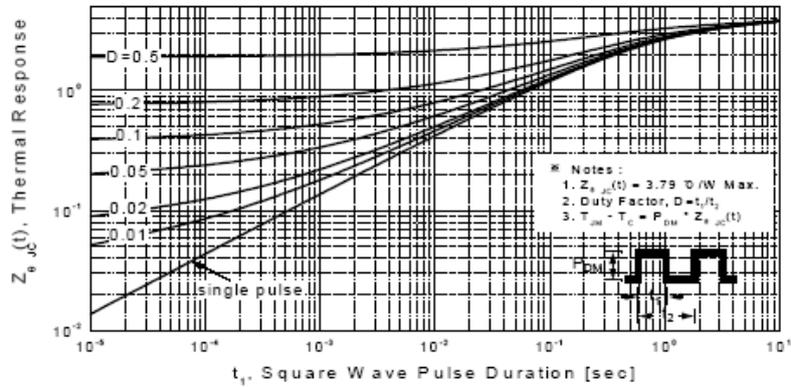
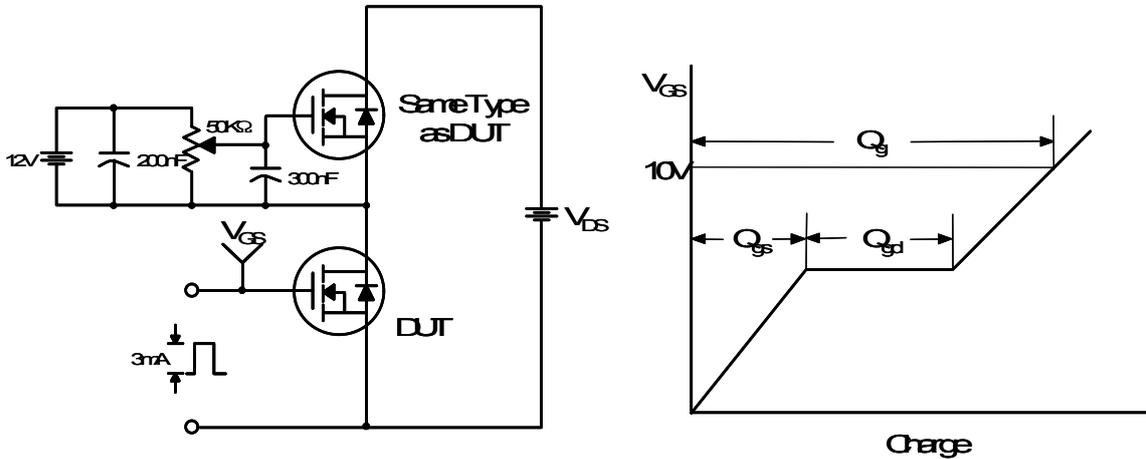


Figure 11-2. Transient Thermal Response Curve for SSS4N65

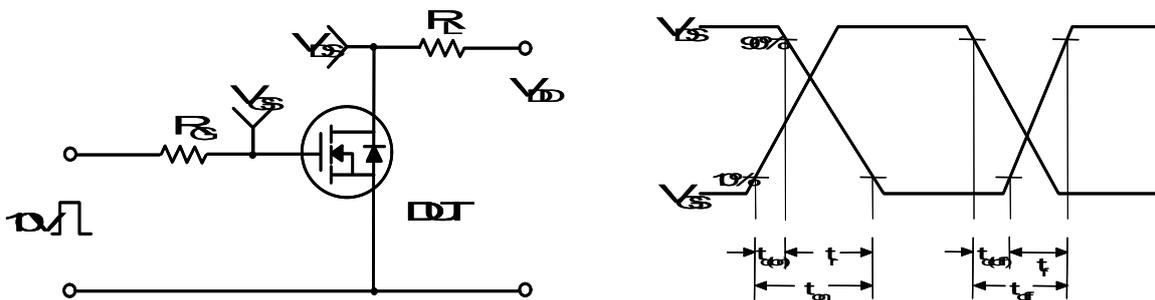
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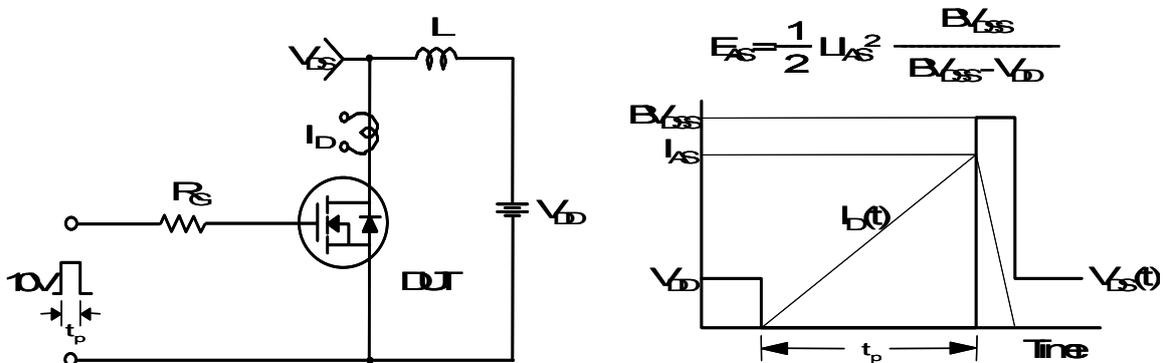
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



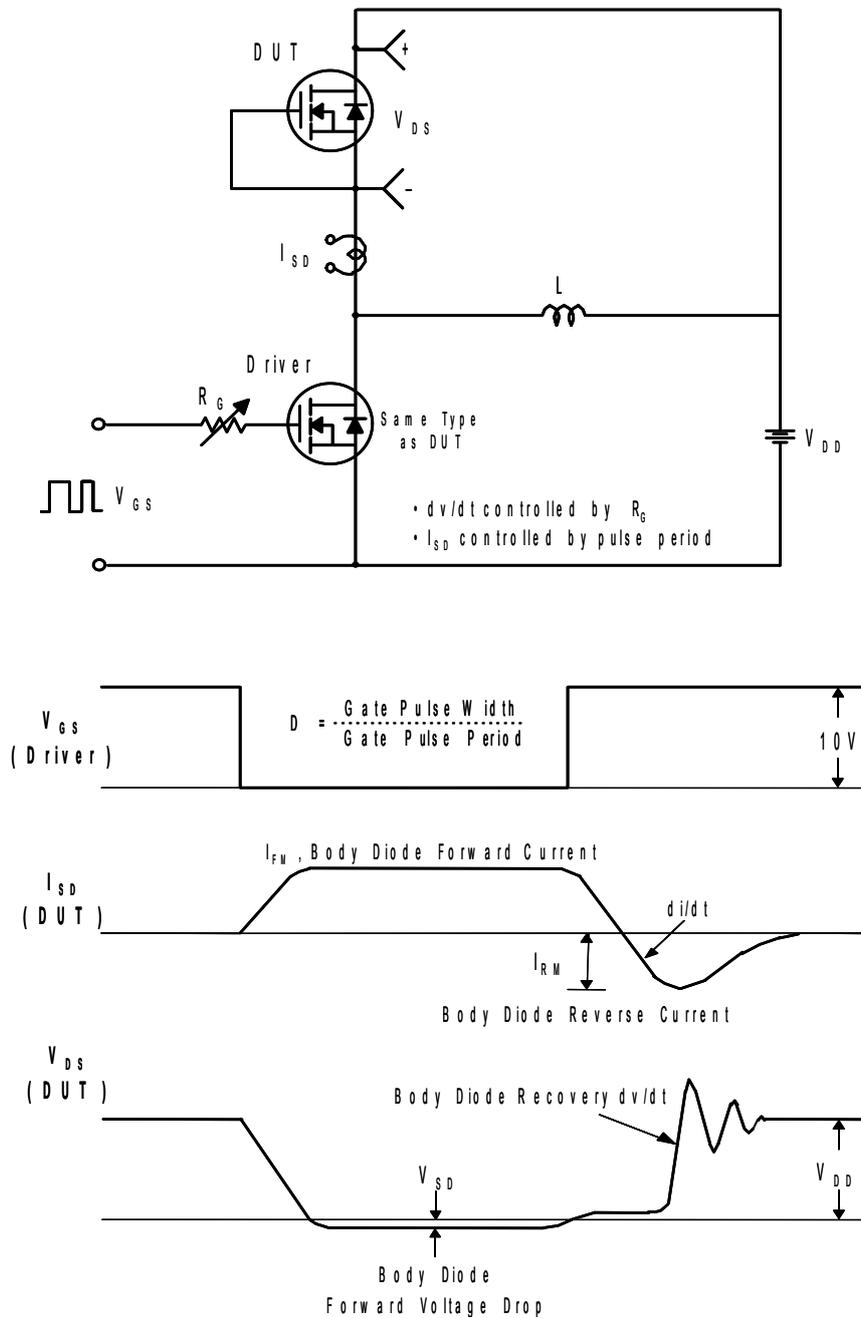
Unclamped Inductive Switching Test Circuit & Waveforms



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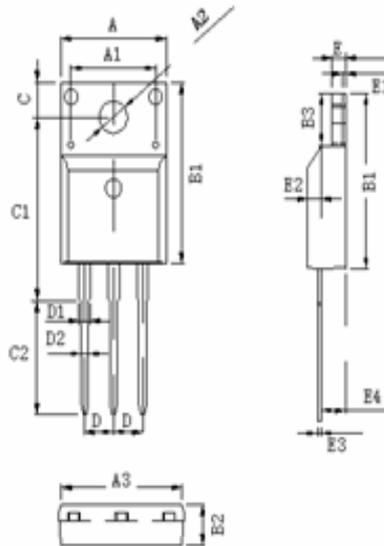
Peak Diode Recovery dv/dt Test Circuit & Waveforms



Package Dimensions

TO-220F

TO-220F 外形尺寸图



DIM.	MILLIMETERS.	
A	10.03 ± 0.20	
A1	7.00	
A2	3.12 ± 0.10	
A3	9.70 ± 0.20	
B1	15.75 ± 0.20	
B2	4.72 ± 0.20	
B3	6.70 ± 0.20	
C	3.30 ± 0.10	
C1	15.80 ± 0.20	
C2	9.80 ± 0.2	
D	Typical 2.54	
D1	1.47 (MAX)	
D2	0.80 ± 0.10	
E	2.55 ± 0.20	
E1	0.70	
E2	1.00 × 45°	
E3	0.50	+0.1 -0.05
E4	2.80 ± 0.20	